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(12) **United States Design Patent**
Ikeda et al.

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(54) **ELECTRICAL TEST INSTRUMENT**

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(73) Assignee: **Fluke Corporation**, Everett, WA (US)

(*) Notice: This patent is subject to a terminal disclaimer.

(**) Term: **14 Years**

(21) Appl. No.: **29/141,875**

(22) Filed: **May 14, 2001**

(51) **LOC (7) Cl.** **10-04**
(52) **U.S. Cl.** **D10/79**
(58) **Field of Search** .... D10/79; 324/99 D, 324/115–117, 126–130, 142, 143, 149, 156, 158 F, 158 P

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Primary Examiner—Antoine Duval Davis

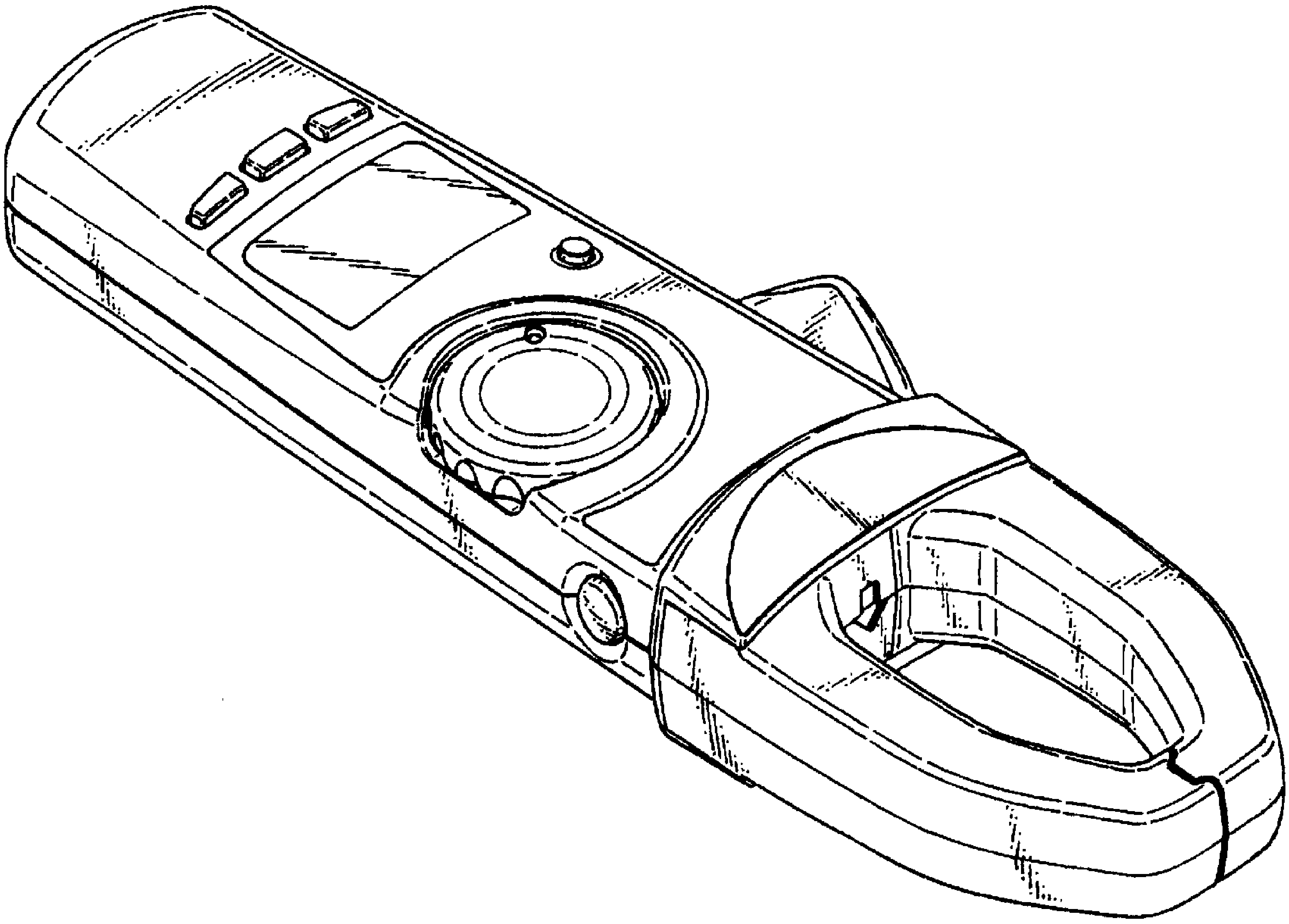
(57) **CLAIM**

The ornamental design for an electrical test instrument, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of a first embodiment of an electrical test instrument showing our new design;
FIG. **2** is a front elevation view thereof;
FIG. **3** is a right side elevation view thereof;
FIG. **4** is a rear elevation view thereof;
FIG. **5** is a left side elevation view thereof;
FIG. **6** is a top plan view thereof; and,
FIG. **7** is a bottom plan view thereof.

1 Claim, 4 Drawing Sheets



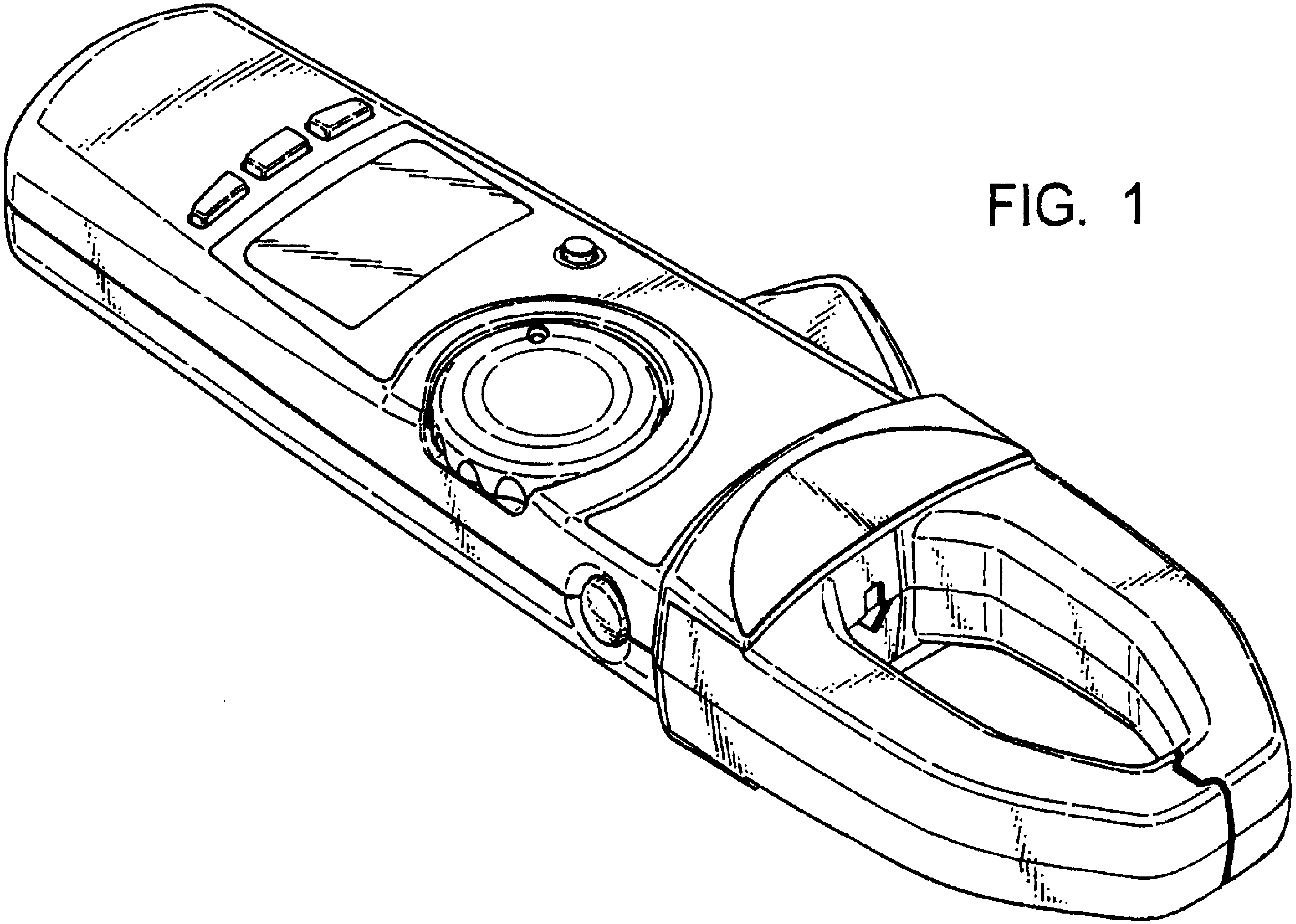


FIG. 1

FIG. 2

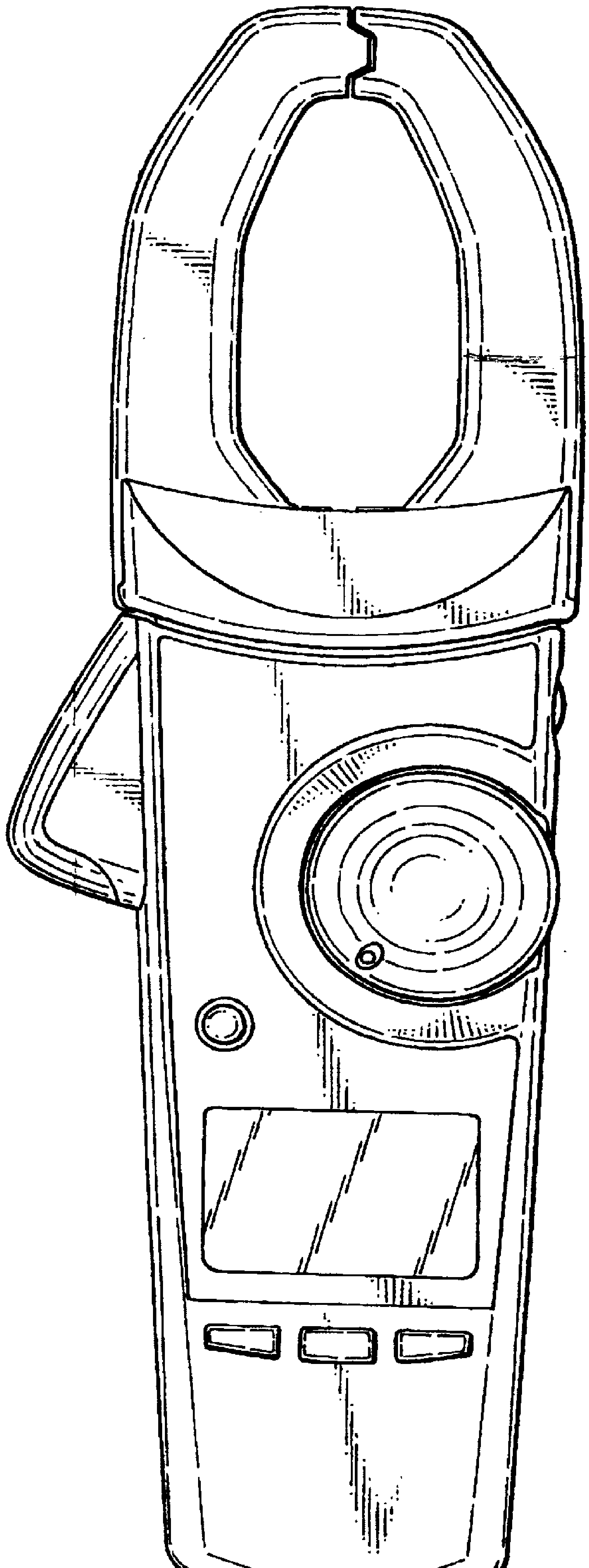


FIG. 3

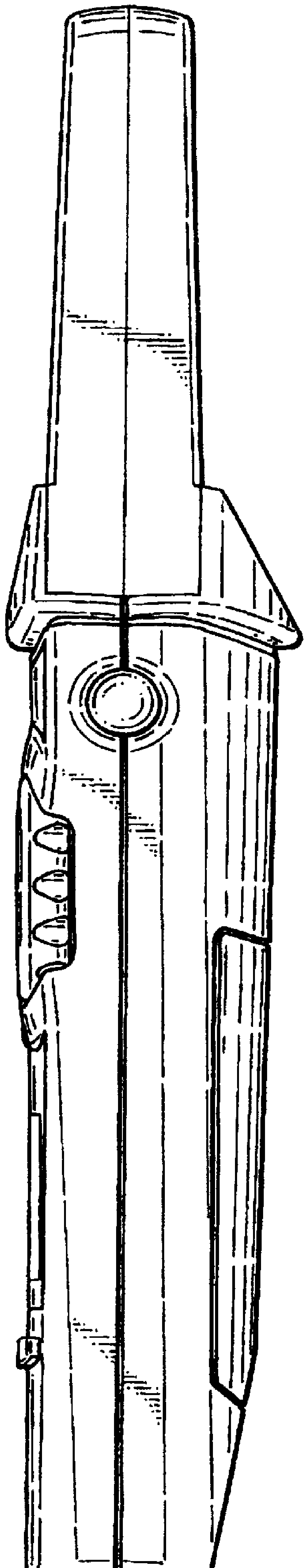


FIG. 4

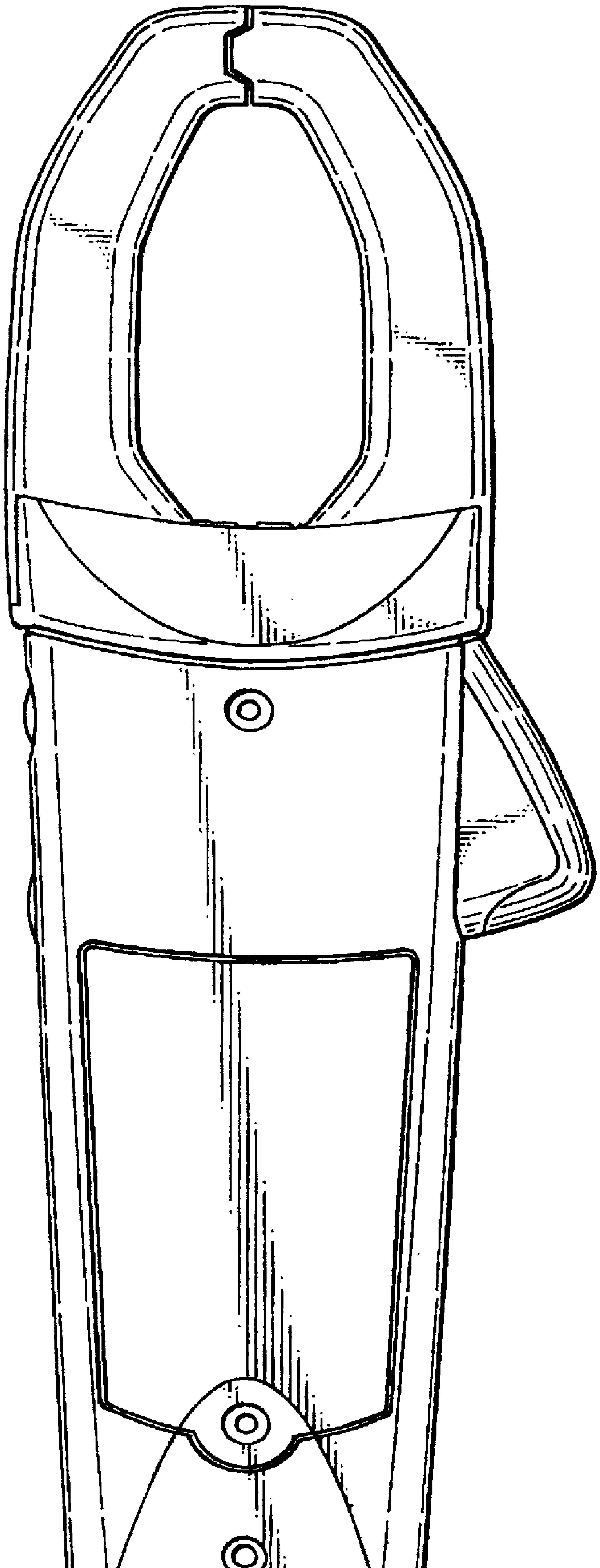


FIG. 5

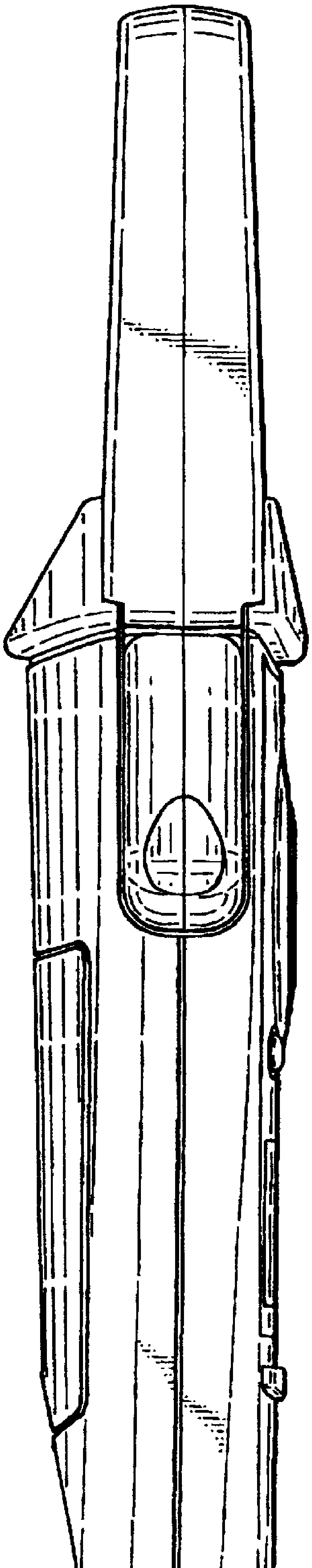


FIG. 6

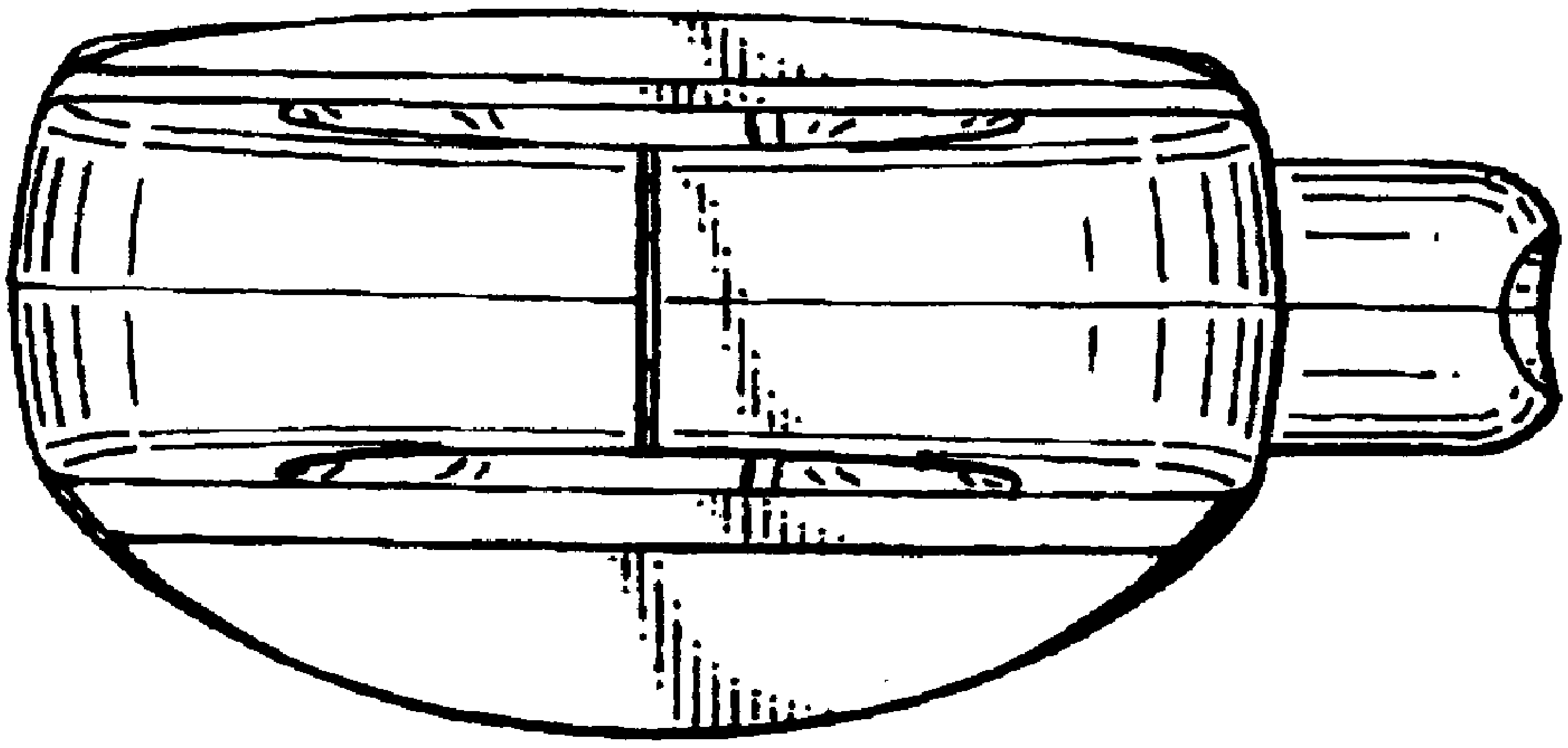


FIG. 7